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| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination SIEMENS ET AL. | |
| | | Examiner Daniel I. Walsh | Art Unit 2876 | Page 1 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-3,897,901 | 08-1975 | Grosswiller et al. | 109/24.1 |
| | B | US-4,166,945 | 09-1979 | Inoyama et al. | 235/379 |
| | C | US-4,253,016 | 02-1981 | Hirose, Minoru | 235/381 |
| | D | US-5,561,281 | 10-1996 | Eda et al. | 235/379 |
| | E | US-6,000,555 | 12-1999 | Anma, Hideyuki | 209/534 |
| | F | US-6,012,048 | 01-2000 | Gustin et al. | 705/39 |
| | G | US-6,145,737 | 11-2000 | Imai et al. | 232/1D |
| | H | US-6,276,602 | 08-2001 | Henderson et al. | 235/379 |
| | I | US-6,516,998 | 02-2003 | Calder et al. | 235/381 |
| | J | US-6,626,357 | 09-2003 | Ross, Ian F. | 235/379 |
| | K | US-6,659,340 | 12-2003 | Siemens, John | 235/379 |
| | L | US-6,663,001 | 12-2003 | Suttie et al. | 235/379 |
| | M | US-6,749,053 | 06-2004 | Ikuta, Yoshiaki | 194/206 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | jp356063664 | 05-1981 | Japan | Kato | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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| | | | | |
|-----------------------------------|--|-----------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination SIEMENS ET AL. | |
| | | Examiner Daniel I. Walsh | Art Unit 2876 | Page 2 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-6,783,061 | 08-2004 | Graef et al. | 235/379 |
| | B | US-2001/0054643 | 12-2001 | Siemens, John | 235/379 |
| | C | US-2002/0074393 | 06-2002 | ANDERSON et al. | 235/379 |
| | D | US-2002/0100399 | 08-2002 | Young, Neil M. | 109/24.1 |
| | E | US-2004/0210515 | 10-2004 | Hughes, Grant | 705/039 |
| | F | US-2004/0226493 | 11-2004 | Siemens et al. | 109/053 |
| | G | US-2002/0035515 | 03-2002 | Moreno, Eli | 705/26 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
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|---|---|---|
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| | V | |
| | W | |
| | X | |

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